



# Am29C861A/Am29C863A

## High Performance CMOS Bus Transceivers

### DISTINCTIVE CHARACTERISTICS

- High-speed CMOS bidirectional bus transceivers
  - T-R delay = 4 ns typical
- Low standby power
- Very high output drive
  - $I_{OL}$  = 48 mA Commercial, 32 mA Military
- 200-mV typical hysteresis on data input ports
- Proprietary edge-rate controlled outputs dramatically reduce undershoots, overshoots, and ground bounce
- Power-up/down disable circuit provides for glitch-free power supply sequencing
- Can be powered off while in 3-state, ideal for card edge interface applications
- Minimal speed degradation with multiple outputs switching
- JEDEC FCT-compatible specs

### GENERAL DESCRIPTION

The Am29C861A and Am29C863A CMOS Bus Transceivers provide high-performance bus interface buffering for wide address/data paths or buses carrying parity. The Am29C861A is a 10-bit bidirectional transceiver; the Am29C863A is a 9-bit transceiver with NORed output enables for maximum control flexibility. Each device features data inputs with 200-mV typical input hysteresis to provide improved noise immunity. The Am29C861A and Am29C863A are produced with AMD's exclusive CS11SA CMOS process, and features a typical propagation delay of 4 ns, as well as an output current drive of 48 mA.

The Am29C861A and Am29C863A incorporate AMD's proprietary edge-controlled outputs in order to minimize simultaneous switching noise (ground bounce), undershoots and overshoots. By controlling the output transient currents, ground bounce and output ringing have

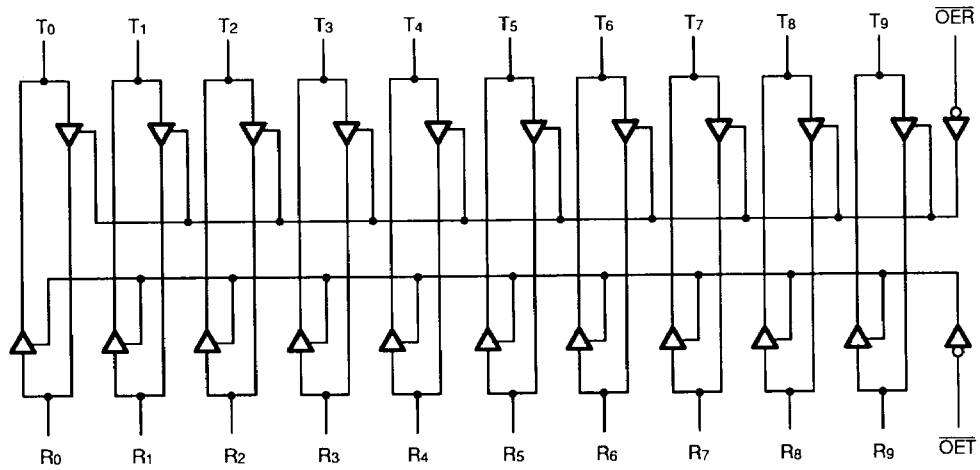
been greatly reduced. A modified AMD output provides a stable, usable voltage level in less time than a non-controlled output.

Additionally, speed degradation due to increasing number of outputs switching is reduced. Together, these benefits of edge-rate control result in significant increase in system performance despite a minor increase in device propagation delay.\*

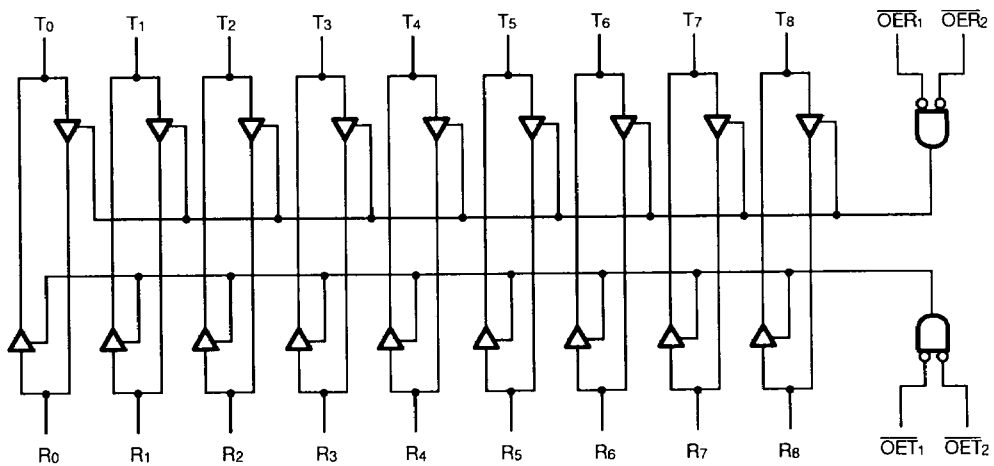
A unique I/O circuitry which utilizes n-channel pull-up transistors (eliminating the parasitic diode to  $V_{CC}$ ) provides for high-impedance outputs during power-off and power-up/down sequencing, thus providing glitch-free operation for card-edge and other active bus applications.

The Am29C861A and Am29C863A are available in the standard package options: DIPs, PLCCs, and SOICs.

\* For more details refer to a Minimization of Ground Bounce Through Output Edge-Rate Control Application Note (See Chapter 3).

**BLOCK DIAGRAMS****Am29C861A**

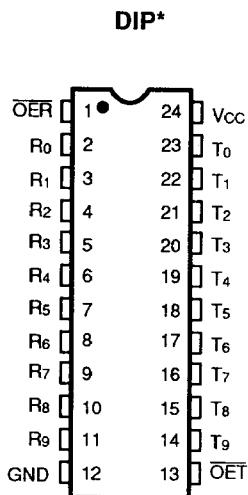
11231-001A

**Am29C863A**

11231-002A

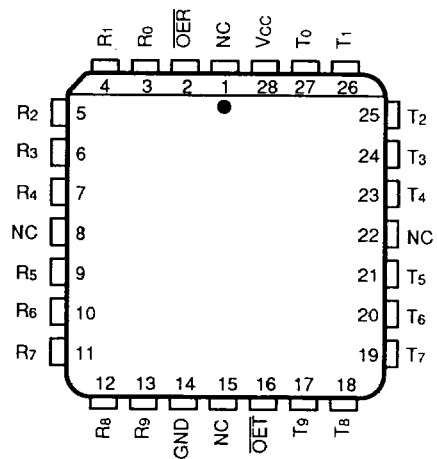
## CONNECTION DIAGRAMS

### Top View Am29C861A



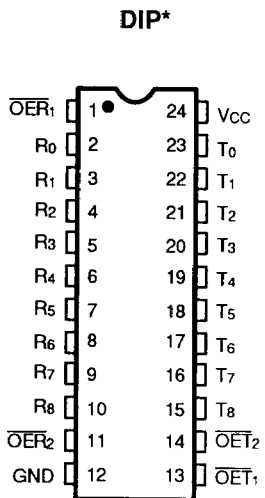
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### PLCC



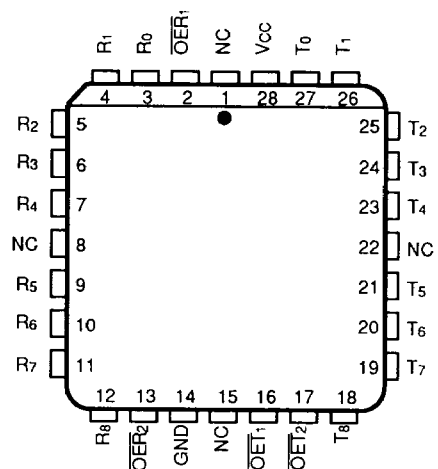
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### Am29C863A



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### PLCC



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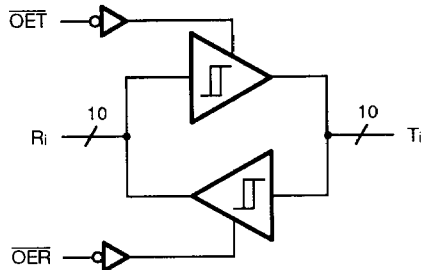
\*Also available in 24-Pin Small Outline Package; pinout identical to DIPs.

**Note:**

Pin 1 is marked for orientation

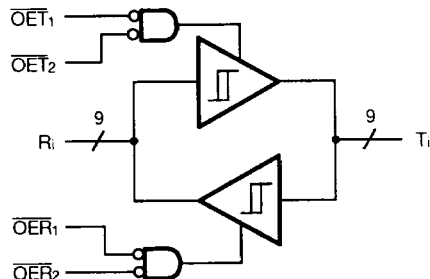
**LOGIC SYMBOLS**

**Am29C861A**



11231-007A

**Am29C863A**



11231-008A

**FUNCTION TABLES**

**Am29C861A**

Inputs				Outputs		Function
$\overline{OET}$	$\overline{OER}$	$R_i$	$T_i$	$R_i$	$T_i$	
L	H	L	N/A	N/A	L	Transmit
L	H	H	N/A	N/A	H	Transmit
H	L	N/A	L	L	N/A	Receive
H	L	N/A	H	H	N/A	Receive
H	H	X	X	Z	Z	Hi-Z

**Am29C863A**

Inputs				Outputs		Function		
$\overline{OET}_1$	$\overline{OET}_2$	$\overline{OER}_1$	$\overline{OER}_2$	$R_i$	$T_i$		$R_i$	$T_i$
L	L	H	X	L	N/A	N/A	L	Transmit
L	L	X	H	L	N/A	N/A	L	Transmit
H	X	L	L	N/A	L	L	N/A	Receive
X	H	L	L	N/A	L	L	N/A	Receive
L	L	H	X	H	N/A	N/A	H	Transmit
L	L	X	H	H	N/A	N/A	H	Transmit
H	X	L	L	N/A	H	H	N/A	Receive
X	H	L	L	N/A	H	H	N/A	Receive
H	X	H	X	X	X	Z	Z	Hi-Z
X	H	X	H	X	X	Z	Z	Hi-Z

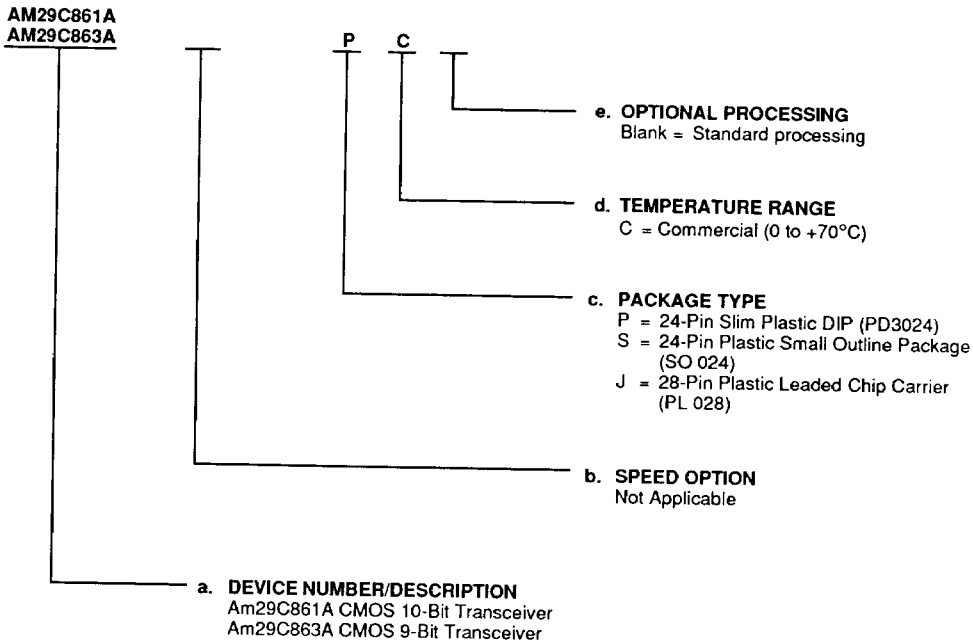
H = HIGH      NC = Not Applicable  
 L = LOW        Z = High Impedance  
 X = Don't Care

## ORDERING INFORMATION

### Standard Products

AMD standard products are available in several packages and operating ranges. The order number (Valid Combination) is formed by a combination of:

- a. Device Number
- b. Speed Option (if applicable)
- c. Package Type
- d. Temperature Range
- e. Optional Processing



Valid Combinations	
AM29C861A	PC, SC, JC
AM29C863A	

#### Valid Combinations

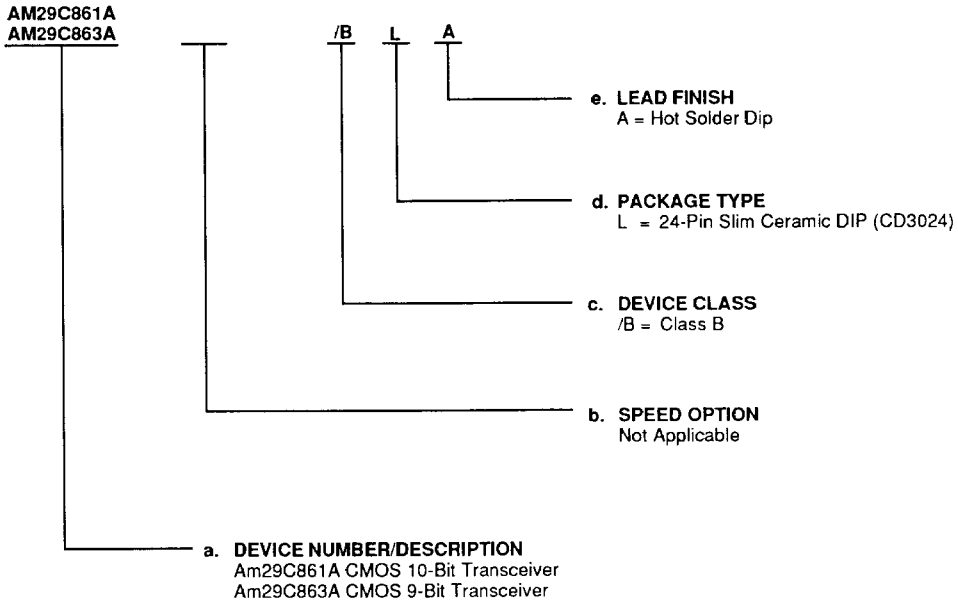
Valid Combinations list configurations planned to be supported in volume for this device. Consult the local AMD sales office to confirm availability of specific valid combinations or to check on newly released combinations, and to obtain additional data on AMD's standard military grade products.

# MILITARY ORDERING INFORMATION

## APL Products

AMD products for Aerospace and Defense applications are available in several packages and operating ranges. APL (Approved Products List) products are fully compliant with MIL-STD-883C requirements. The order number (Valid Combination) is formed by a combination of:

- a. Device Number
- b. Speed Option (if applicable)
- c. Device Class
- d. Package Type
- e. Lead Finish



Valid Combinations	
AM29C861A	/BLA
AM29C863A	

### Valid Combinations

Valid Combinations list configurations planned to be supported in volume for this device. Consult the local AMD sales office to confirm availability of specific valid combinations, or to check on newly released combinations.

### Group A Tests

Group A tests consist of Subgroups 1, 2, 3, 7, 8, 9, 10, 11.

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**PIN DESCRIPTION****Am29C861A Only****OER****Output Enable Receive (Input, Active Low)**

When LOW in conjunction with  $\overline{\text{OET}}$  HIGH, the devices are in the Receive mode ( $R_i$  are outputs,  $T_i$  are inputs).

**OET****Output Enable Transmit (Input, Active Low)**

When LOW in conjunction with  $\overline{\text{OER}}$  HIGH, the devices are in the Transmit mode ( $R_i$  are inputs,  $T_i$  are output).

 **$R_i$** **Receive Port (Input/Output)**

$R_i$  are the 10-bit data inputs in the Transmit mode, and the outputs in the Receive mode.

 **$T_i$** **Transmit Port (Input/Output)**

$T_i$  are the 10-bit data outputs in the Transmit mode, and the inputs in the Receive mode.

**Am29C863A Only** **$\overline{\text{OER}}_i$** **Output Enables Receive (Input, Active Low)**

When both  $\overline{\text{OER}}_1$  and  $\overline{\text{OER}}_2$  are LOW while  $\overline{\text{OET}}_1$  or  $\overline{\text{OET}}_2$  (or both) are HIGH, the device is in the Receive mode ( $R_i$  are outputs,  $T_i$  are inputs).

 **$\overline{\text{OET}}_i$** **Output Enables Transmit (Input, Active Low)**

When both  $\overline{\text{OET}}_1$  and  $\overline{\text{OET}}_2$  are LOW while  $\overline{\text{OER}}_1$  or  $\overline{\text{OER}}_2$  (or both) are HIGH, the device is in the Transmit mode ( $R_i$  are inputs,  $T_i$  are outputs).

 **$R_i$** **Receive Port (Input/Output)**

$R_i$  are the 9-bit data inputs in the Transmit mode, and the outputs in the Receive mode.

 **$T_i$** **Transmit Port (Input/Output)**

$T_i$  are the 9-bit data outputs in the Transmit mode, and the inputs in the Receive mode.

**ABSOLUTE MAXIMUM RATINGS**

Storage Temperature	-65 to +150°C
Supply Voltage to Ground	
Potential Continuous	-0.5 V to +7.0 V
DC Output Voltage	-0.5 V to +6.0 V
DC Input Voltage	-0.5 V to +6.0 V
DC Output Diode Current:	Into Output + 50 mA
	Out of Output - 50 mA
DC Input Diode Current:	Into Input + 20 mA
	Out of Input - 20 mA
DC Output Current:	Into Output + 100 mA
	Out of Output - 100 mA

Total DC Ground Current ( $n \times I_{OL} + m \times I_{OCT}$ ) mA (Note 1)

Total DC  $V_{CC}$  Current ( $n \times I_{OH} + m \times I_{OCT}$ ) mA (Note 1)

Stresses above those listed under Absolute Maximum Ratings may cause permanent device failure. Functionality at or above these limits is not implied. Exposure to absolute maximum ratings for extended periods may affect device reliability.

**OPERATING RANGES****Commercial (C) Devices**

Ambient Temperature ( $T_A$ )	0 to +70°C
Supply Voltage ( $V_{CC}$ )	+4.5 V to +5.5 V

**Military (M) Devices**

Ambient Temperature ( $T_A$ )	-55 to +125°C
Supply Voltage ( $V_{CC}$ )	+4.5 V to +5.5 V

Operating ranges define those limits between which the functionality of the device is guaranteed.

**DC CHARACTERISTICS over COMMERCIAL operating ranges unless otherwise specified (for APL Products, Group A, Subgroups 1, 2, 3 are tested unless otherwise noted)**

Parameter Symbol	Parameter Description	Test Conditions		Min.	Max.	Unit
$V_{OH}$	Output HIGH Voltage	$V_{CC} = 4.5 \text{ V}$ $V_{IN} = V_{IH} \text{ or } V_{IL}$	$I_{OH} = -15 \text{ mA}$	2.4		V
$V_{OL}$	Output LOW Voltage	$V_{CC} = 4.5 \text{ V}$ $V_{IN} = V_{IH} \text{ or } V_{IL}$	MIL, $I_{OL} = 32 \text{ mA}$ COM'L, $I_{OL} = 48 \text{ mA}$		0.5 0.5	V
$V_{IH}$	Input HIGH Voltage	Guaranteed Input Logical HIGH Voltage for all Inputs (Note 2)		2.0		V
$V_{IL}$	Input LOW Voltage	Guaranteed Input Logical LOW Voltage for all Inputs (Note 2)			0.8	V
$V_I$	Input Clamp Voltage	$V_{CC} = 4.5 \text{ V}$ , $I_{IN} = -18 \text{ mA}$			-1.2	V
$I_{IL}$	Input LOW Current	$V_{CC} = 5.5 \text{ V}$ Input Only	$V_{IN} = 0 \text{ V}$		-5	$\mu\text{A}$
$I_{IH}$	Input HIGH Current	$V_{CC} = 5.5 \text{ V}$ Input Only	$V_{IN} = 5.5 \text{ V}$		5	$\mu\text{A}$
$I_{OZH}$	Output Off-State Current (High Impedance)	$V_{CC} = 5.5 \text{ V}$ I/O Port	$V_{OUT} = 5.5 \text{ V}$		10	$\mu\text{A}$
$I_{OZL}$		$V_{CC} = 5.5 \text{ V}$ I/O Port	$V_{OUT} = 0 \text{ V}$		-10	$\mu\text{A}$
$I_{SC}$	Output Short-Circuit Current	$V_{CC} = 5.5 \text{ V}$ , $V_O = 0 \text{ V}$ (Note 3)		-60		mA
$I_{CCQ}$	Static Supply Current	$V_{CC} = 5.5 \text{ V}$ Outputs Open	$V_{IN} = V_{CC}$ or GND	MIL	1.5	mA
				COM'L	1.2	
$I_{CCT}$			$V_{IN} = 3.4 \text{ V}$	Data Input $\overline{OER}_1$ , $\overline{OER}_2$ $\overline{OET}_1$ , $\overline{OET}_2$	1.5 3.0	mV/ Bit
$I_{CCD+}$	Dynamic Supply Current	$V_{CC} = 5.5 \text{ V}$ (Note 4)	Outputs Open Outputs Loaded	275 400	$\mu\text{A}/$ MHz/ Bit	

**Notes:**

1.  $n$  = number of outputs,  $m$  = number of inputs.
2. Input thresholds are tested in combination with other DC parameters or by correlation.
3. Not more than one output should be shorted at a time. Duration should not exceed 100 milliseconds.
4. Measured at a frequency  $\leq 10 \text{ MHz}$  with 50% duty cycle.

† Not included in Group A tests.



**SWITCHING CHARACTERISTICS** for light capacitive loading over operating ranges unless otherwise specified (for APL Products, Group A, Subgroups 9, 10, 11 are tested unless otherwise noted)

**Am29C861A**

Parameter Symbol	Parameter Description	Test Conditions*	Commercial		Military		Unit
			Min.	Max.	Min.	Max.	
t <sub>PLH</sub>	Propagation Delay from R <sub>i</sub> to T <sub>i</sub> or T <sub>i</sub> to R <sub>i</sub> (Note 1)	C <sub>L</sub> = 50 pF R <sub>1</sub> = 500 Ω R <sub>2</sub> = 500 Ω	2	7	2	8	ns
t <sub>PHL</sub>			2	8	2	9	ns
t <sub>ZH</sub>	Output Enable Time $\overline{OET}$ to T <sub>i</sub> or $\overline{OER}$ to R <sub>i</sub>		2	10	2	11	ns
t <sub>ZL</sub>			2	12.5	2	13.5	ns
t <sub>HZ</sub>	Output Disable Time $\overline{OET}$ to T <sub>i</sub> or $\overline{OER}$ to R <sub>i</sub>		1.5	9	1.5	10	ns
t <sub>LZ</sub>			1.5	10	1.5	11	ns

**Am29C863A**

Parameter Symbol	Parameter Description	Test Conditions*	Commercial		Military		Unit
			Min.	Max.	Min.	Max.	
t <sub>PLH</sub>	Propagation Delay from R <sub>i</sub> to T <sub>i</sub> or T <sub>i</sub> to R <sub>i</sub> (Note 1)	C <sub>L</sub> = 50 pF R <sub>1</sub> = 500 Ω R <sub>2</sub> = 500 Ω	2	7	2	8	ns
t <sub>PHL</sub>			2	8	2	9	ns
t <sub>ZH</sub>	Output Enable Time $\overline{OET}$ to T <sub>i</sub> or $\overline{OER}$ to R <sub>i</sub>		2	10.5	2	11.5	ns
t <sub>ZL</sub>			2	12.5	2	13.5	ns
t <sub>HZ</sub>	Output Disable Time $\overline{OET}$ to T <sub>i</sub> or $\overline{OER}$ to R <sub>i</sub>		1.5	10	1.5	11	ns
t <sub>LZ</sub>			1.5	11	1.5	12	ns

\* See Test Circuit and Waveforms listed in Chapter 2.

**Notes:**

1. For more details refer to a Minimization of Ground Bounce Through Output Edge-Rate Control Application Note (See Chapter 3).

**SWITCHING CHARACTERISTICS for heavy capacitive loading over operating ranges unless otherwise specified (Note 2)****Am29C861A**

Parameter Symbol	Parameter Description	Test Conditions*	Commercial		Military		Unit
			Min.	Max.	Min.	Max.	
t <sub>PLH</sub>	Propagation Delay from R <sub>i</sub> to T <sub>i</sub> or T <sub>i</sub> to R <sub>i</sub> (Note 1)	C <sub>L</sub> = 300 pF R <sub>1</sub> = 500 Ω R <sub>2</sub> = 500 Ω	2	14.5	2	15.5	ns
t <sub>PHL</sub>			2	15.5	2	16.5	ns
t <sub>ZH</sub>	Output Enable Time $\overline{OET}$ to T <sub>i</sub> or $\overline{OER}$ to R <sub>i</sub>		2	16.5	2	17.5	ns
t <sub>ZL</sub>			2	20.5	2	21.5	ns
t <sub>HZ</sub>	Output Disable Time $\overline{OET}$ to T <sub>i</sub> or $\overline{OER}$ to R <sub>i</sub>	C <sub>L</sub> = 5 pF R <sub>1</sub> = 500 Ω R <sub>2</sub> = 500 Ω	1.5	7	1.5	8	ns
t <sub>LZ</sub>			1.5	8.5	1.5	9.5	ns

**Am29C863A**

Parameter Symbol	Parameter Description	Test Conditions*	Commercial		Military		Unit
			Min.	Max.	Min.	Max.	
t <sub>PLH</sub>	Propagation Delay from R <sub>i</sub> to T <sub>i</sub> or T <sub>i</sub> to R <sub>i</sub> (Note 1)	C <sub>L</sub> = 300 pF R <sub>1</sub> = 500 Ω R <sub>2</sub> = 500 Ω	2	14.5	2	15.5	ns
t <sub>PHL</sub>			2	15.5	2	16.5	ns
t <sub>ZH</sub>	Output Enable Time $\overline{OET}$ to T <sub>i</sub> or $\overline{OER}$ to R <sub>i</sub>		2	16.5	2	17.5	ns
t <sub>ZL</sub>			2	20.5	2	21.5	ns
t <sub>HZ</sub>	Output Disable Time $\overline{OET}$ to T <sub>i</sub> or $\overline{OER}$ to R <sub>i</sub>	C <sub>L</sub> = 5 pF R <sub>1</sub> = 500 Ω R <sub>2</sub> = 500 Ω	1.5	7	1.5	8	ns
t <sub>LZ</sub>			1.5	8.5	1.5	9.5	ns

\* See Test Circuit and Waveforms listed in Chapter 2.

**Notes:**

1. For more details refer to a Minimization of Ground Bounce Through Output Edge-Rate Control Application Note (See Chapter 3).
2. These parameters are guaranteed by characterization but not production tested.